

## General Description

The AON3611 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs may be used in inverter and other applications.

## Features

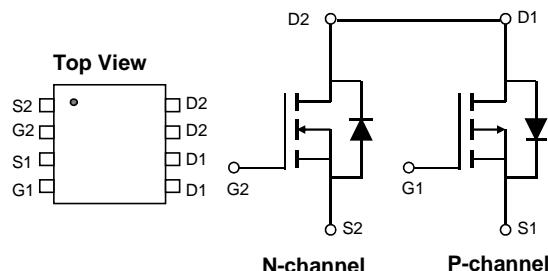
N-channel      P-channel

$V_{DS}$  (V) = 30V       $V_{DS}$  (V) = -30V

$I_D$  = 5A       $I_D$  = -6A      ( $V_{GS}$  =  $\pm 10$ V)

$R_{DS(ON)}$  < 50m $\Omega$        $R_{DS(ON)}$  < 38m $\Omega$       ( $V_{GS}$  =  $\pm 10$ V)

$R_{DS(ON)}$  < 70m $\Omega$        $R_{DS(ON)}$  < 62m $\Omega$       ( $V_{GS}$  =  $\pm 4.5$ V)



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Max N-channel	Max P-channel	Units
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current	$I_D$	5	-6	A
$T_A=70^\circ\text{C}$	$I_D$	3.8	-4.7	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	20	-30	W
$T_A=25^\circ\text{C}$	$P_D$	2.1	2.5	
$T_A=70^\circ\text{C}$	$P_D$	1.3	1.6	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	°C

### Thermal Characteristics: N-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	50	60	°C/W
Steady-State		80	98	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	48	58	°C/W

### Thermal Characteristics: P-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	40	50	°C/W
Steady-State		70	85	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	38	46	°C/W

N-channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.5	2	2.5	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	20			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=5\text{A}$ $T_J=125^\circ\text{C}$	40	50		$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3\text{A}$	64	80		
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=5\text{A}$	53	70		$\text{m}\Omega$
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$	0.79	1		V
$I_S$	Maximum Body-Diode Continuous Current				1.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		170		pF
$C_{\text{oss}}$	Output Capacitance			35		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			23		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1.7	3.5	5.3	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=5\text{A}$		4.05	10	nC
$Q_g(4.5\text{V})$	Total Gate Charge			2	6	nC
$Q_{\text{gs}}$	Gate Source Charge			0.55		nC
$Q_{\text{gd}}$	Gate Drain Charge			1		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=3\Omega, R_{\text{GEN}}=3\Omega$		4.5		ns
$t_r$	Turn-On Rise Time			1.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			18.5		ns
$t_f$	Turn-Off Fall Time			15.5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		7.5		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		2.5		nC

A. The value of  $R_{\text{qJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{qJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{qJL}}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300ms pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

N-channel TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

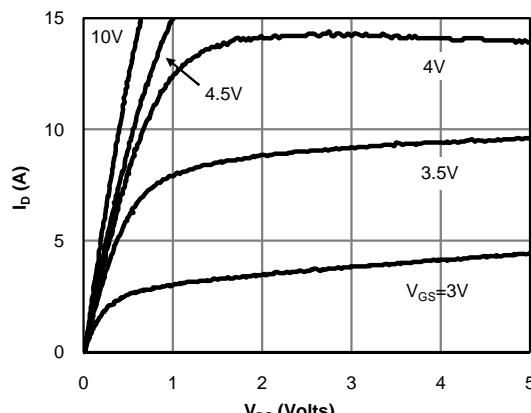


Fig 1: On-Region Characteristics (Note E)

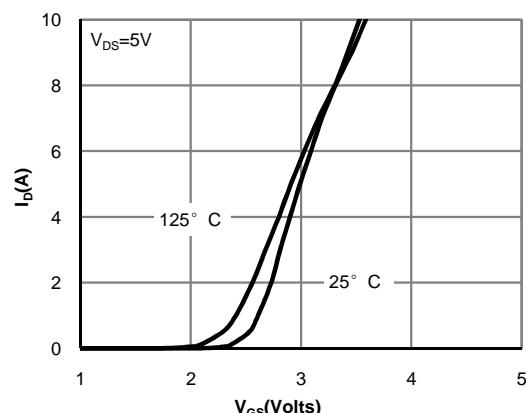


Figure 2: Transfer Characteristics (Note E)

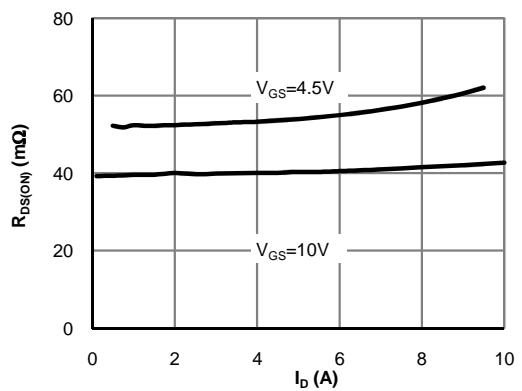


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

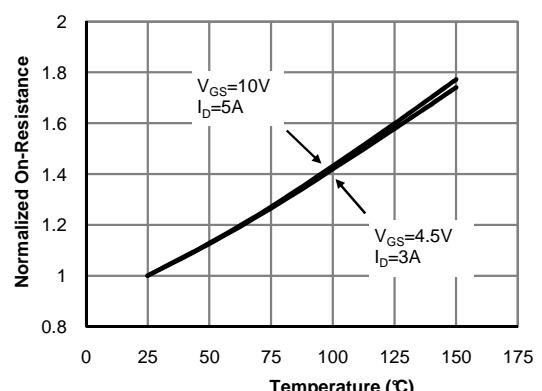


Figure 4: On-Resistance vs. Junction Temperature (Note E)

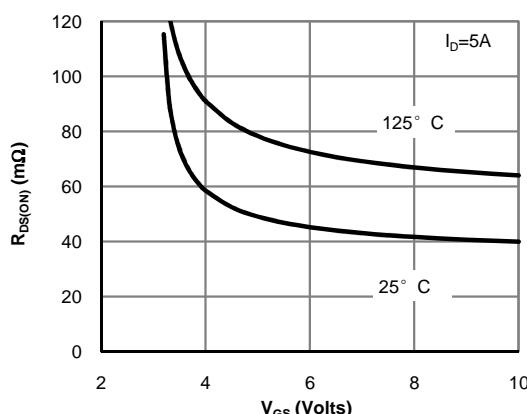


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

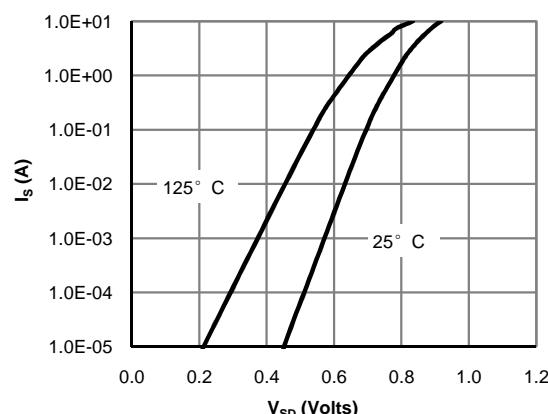


Figure 6: Body-Diode Characteristics (Note E)

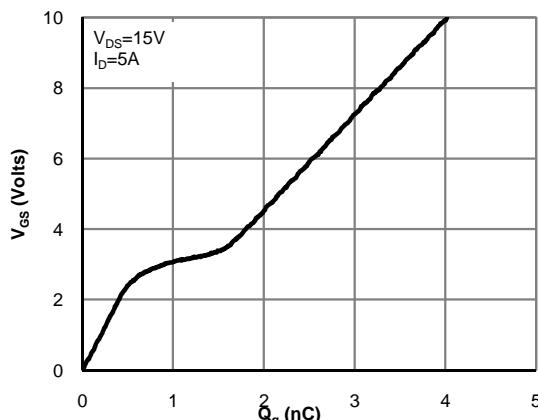
**N-channel TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 7: Gate-Charge Characteristics

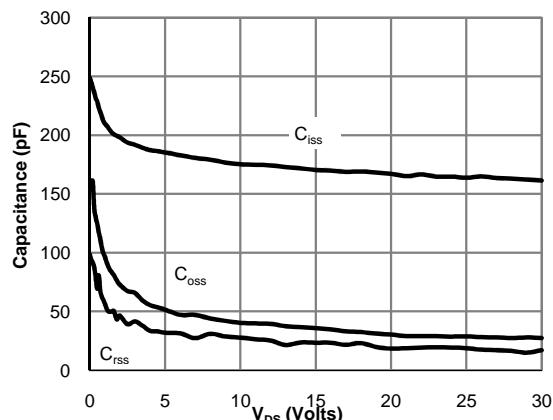


Figure 8: Capacitance Characteristics

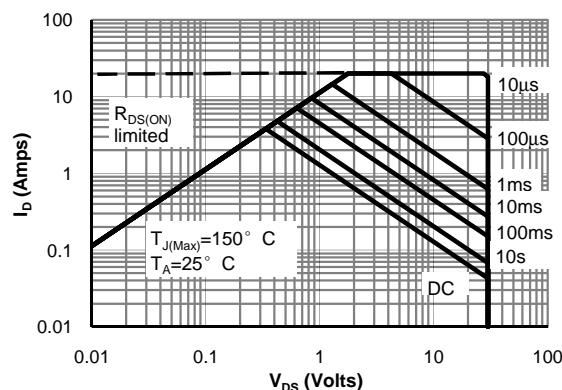


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

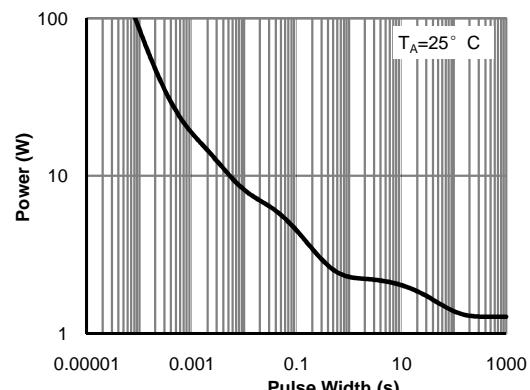
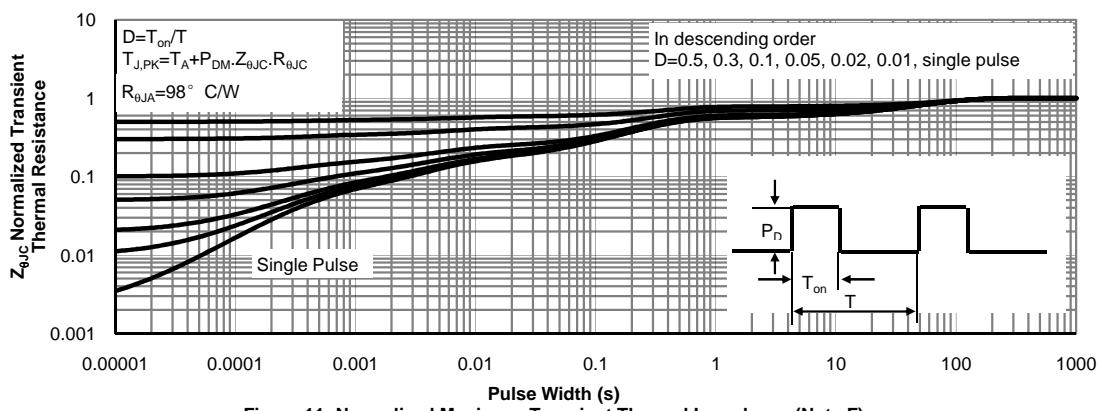
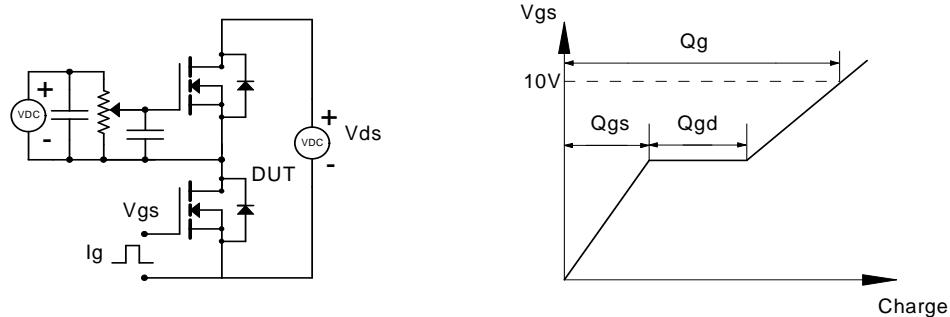


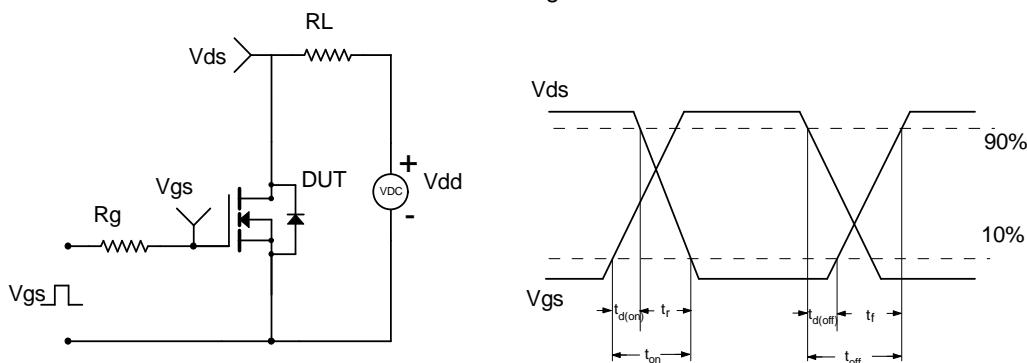
Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)



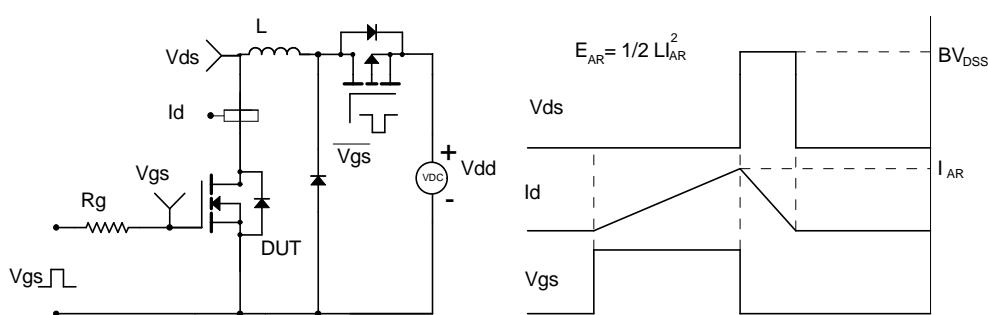
Gate Charge Test Circuit & Waveform



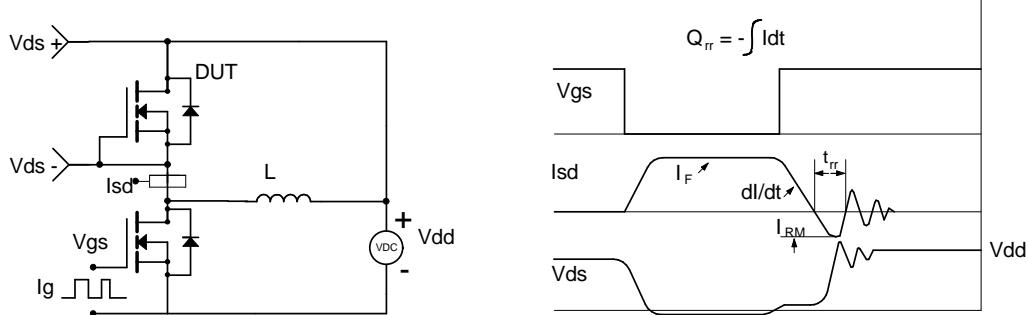
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



**P-channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.4	-1.9	-2.4	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-6\text{A}$ $T_J=125^\circ\text{C}$	30	38		$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-4\text{A}$	45	57		
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-6\text{A}$	46	62		$\text{m}\Omega$
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$	-0.76	-1		V
$I_S$	Maximum Body-Diode Continuous Current				-2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		520		pF
$C_{\text{oss}}$	Output Capacitance		100			pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		65			pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	7.5	11.5		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-6\text{A}$		9.2	20	nC
$Q_g(4.5\text{V})$	Total Gate Charge		4.6	10		nC
$Q_{\text{gs}}$	Gate Source Charge		1.6			nC
$Q_{\text{gd}}$	Gate Drain Charge		2.2			nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=2.5\Omega, R_{\text{GEN}}=3\Omega$	7.5			ns
$t_r$	Turn-On Rise Time		5.5			ns
$t_{\text{D(off)}}$	Turn-Off Delay Time		19			ns
$t_f$	Turn-Off Fall Time		7			ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-6\text{A}, dI/dt=100\text{A}/\mu\text{s}$	11			ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-6\text{A}, dI/dt=100\text{A}/\mu\text{s}$	5.3			nC

A. The value of  $R_{\text{qJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{qJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{qJL}}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300ms pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

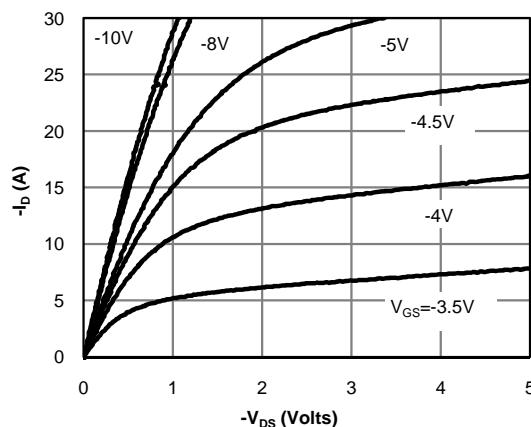
**P-channel TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Fig 1: On-Region Characteristics (Note E)

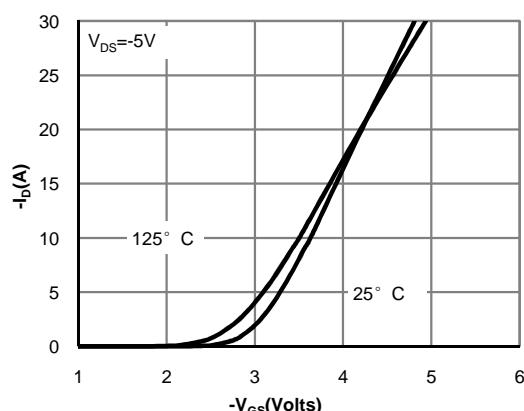


Figure 2: Transfer Characteristics (Note E)

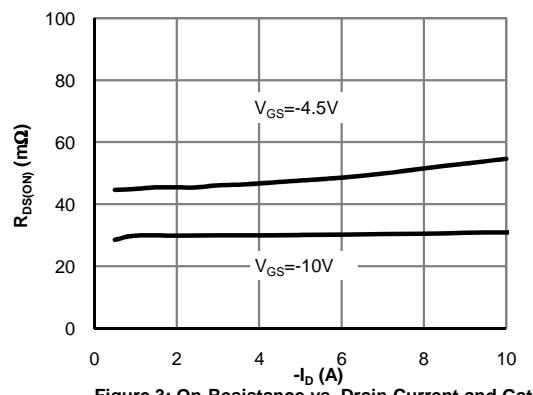


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

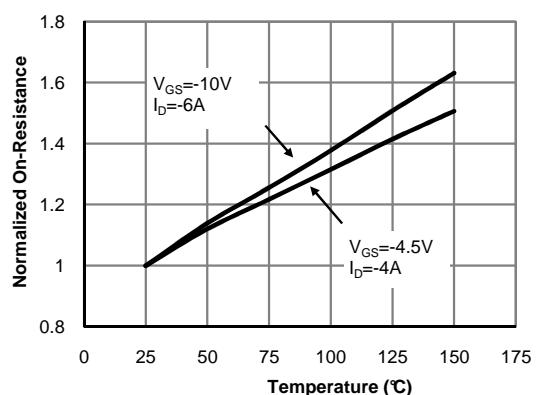


Figure 4: On-Resistance vs. Junction Temperature (Note E)

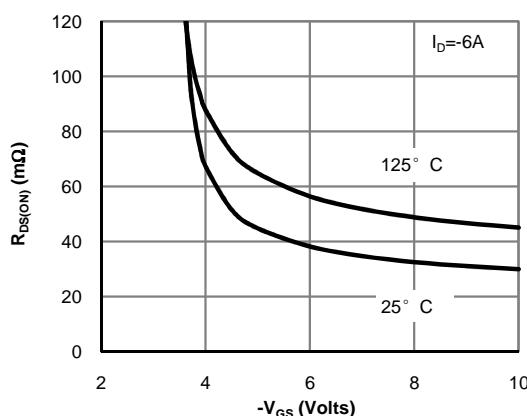


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

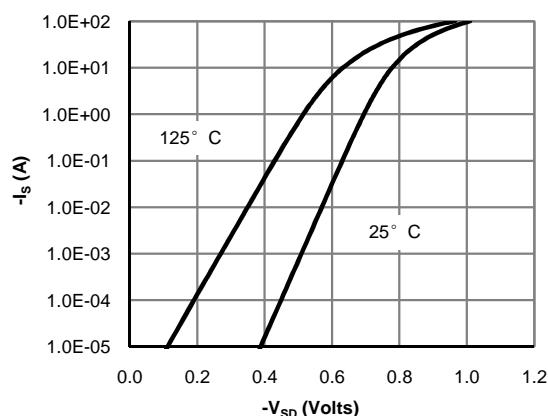
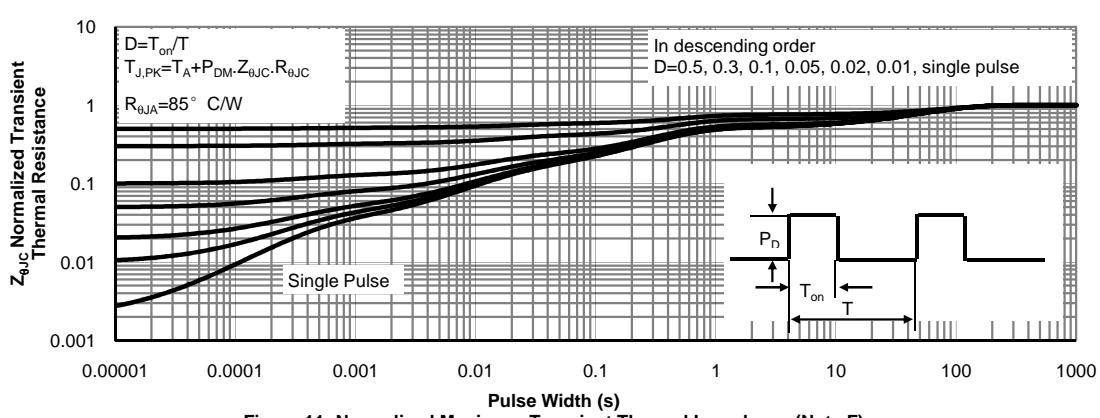
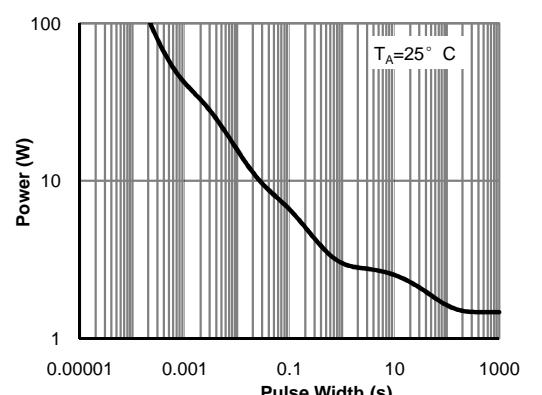
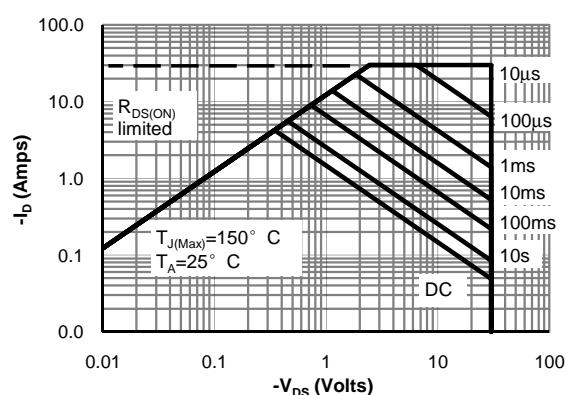
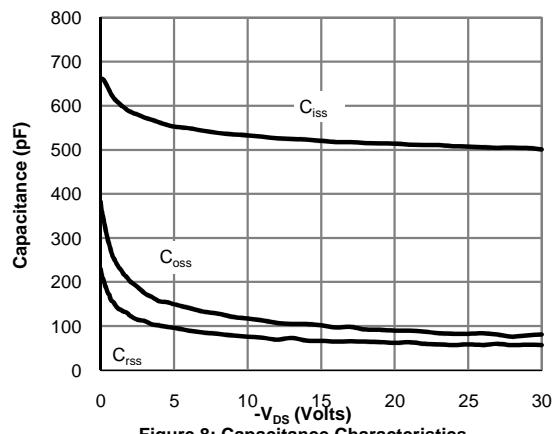
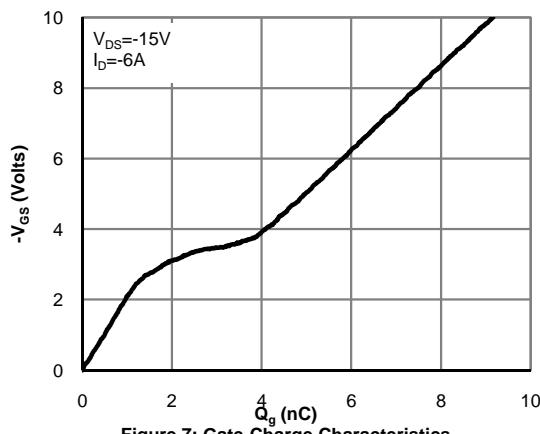
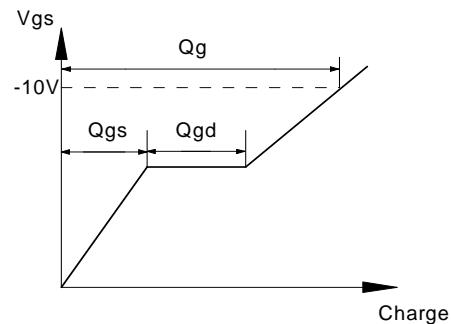
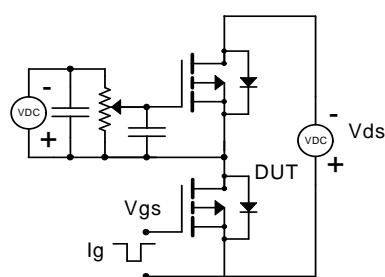


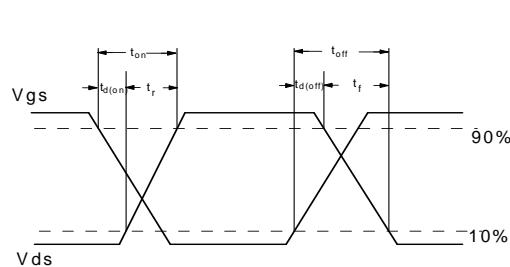
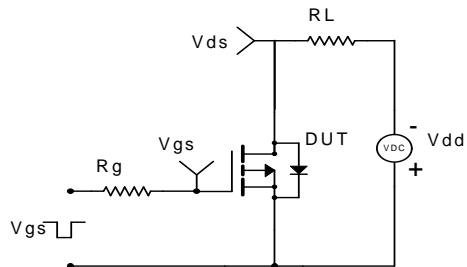
Figure 6: Body-Diode Characteristics (Note E)

**P-channel TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


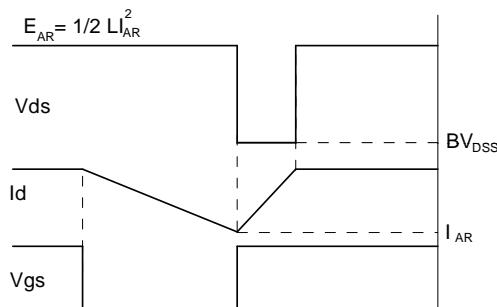
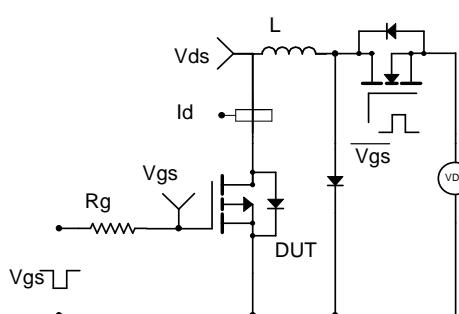
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

